TOSHIBA TRANSISTOR SILICON PNP EPITAXIAL TYPE (PCT PROCESS)

2 S A 1 9 3 3

HIGH CURRENT SWITCHING APPLICATIONS

• Low Saturation Voltage

: $V_{CE (sat)} = -0.4V$ (Max.) at $I_{C} = -2 A$

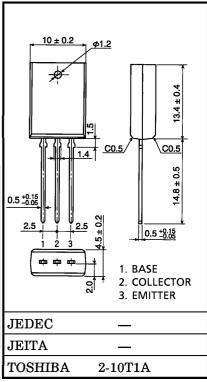
• High Speed Switching Time : $t_{stg} = 1.0 \,\mu s$ (Typ.)

• Complementary to 2SC5175

MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Collector-Base Voltage	v_{CBO}	-60	V
Collector-Emitter Voltage	v_{CEO}	-50	V
Emitter-Base Voltage	$V_{ m EBO}$	-5	V
Collector Current	$I_{\mathbf{C}}$	-5	A
Base Current	I _B	-1	A
Collector Power Dissipation	PC	1.8	W
Junction Temperature	T_{j}	150	°C
Storage Temperature Range	$ m T_{stg}$	-55~150	°C

INDUSTRIAL APPLICATIONS Unit in mm

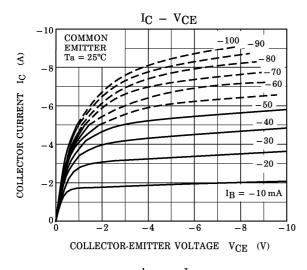


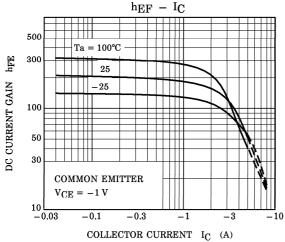
Weight: 1.5 g (Typ.)

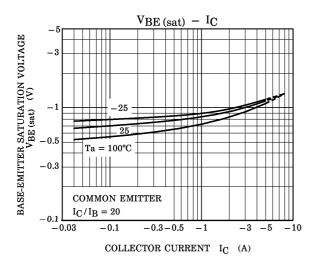
ELECTRICAL CHARACTERISTICS (Ta = 25°C)

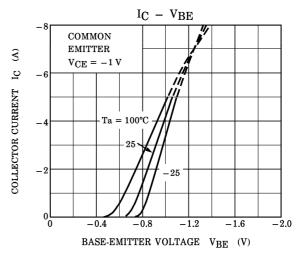
CHARA	ACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Collector Cu	it-off Current	I_{CBO}	$V_{CB} = -50 \text{ V}, I_{E} = 0$	_	_	-1	μ A
Emitter Cut	-off Current	$I_{ m EBO}$	$V_{EB} = -5 V, I_{C} = 0$		_	-1	μ A
Collector-En Voltage	nitter Breakdown	V (BR) CEO	$I_{\rm C} = -10 {\rm mA}, \; I_{\rm B} = 0$	-50	_	_	V
DC Current Gain		h _{FE (1)}	$V_{CE} = -1 V, I_{C} = -1 A$	100	_	320	
		h _{FE (2)}	$V_{CE} = -1 V, I_{C} = -3 A$	60		-	
Saturation	Collector-Emitter	V _{CE} (sat)	$I_C = -2 A, I_B = -0.15 A$		-0.2	-0.4	\mathbf{v}
Voltage	Base-Emitter	V _{BE (sat)}	$I_C = -3 \text{ A}, I_B = -0.15 \text{ A}$	_	-0.9	-1.5	'
Transition I	requency	${ m f_T}$	$V_{CE} = -4 V, I_{C} = -1 A$	-	60	_	MHz
Collector Ou	tput Capacitance	C_{ob}	$V_{CB} = -10 V, I_{E} = 0, f = 1 MHz$		170	1	pF
Switching S	Turn-on Time	t _{on}	INPUT IB2 OUTPUT IB2 OUTPUT	1	0.1	_	
	Storage Time	$t_{ ext{stg}}$	I_{B1} I_{B1} I_{B1} V_{CC}		1.0	_	μ s
	Fall Time	t_f	$-I_{B1} = I_{B2} = 0.15 \text{ A} -30 \text{ V}$ DUTY CYCLE $\leq 1\%$		0.1	_	

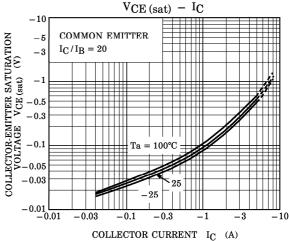
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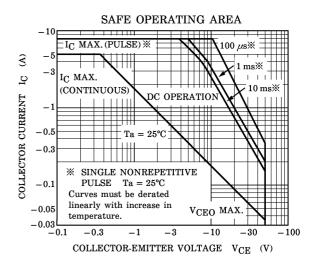












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